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HIDEHIKO KIRA, KAWASAKI-SHI, JAPAN: ANAOKI ISHIKAWA, KAWASAKI-SHI, JAPAN. **CONTINUING DATA***********************************	
FOREIGN/PCT APPLICATIONS**********************************	* 088762 institution
Verified and Acknowledged Examiner's initials ARMSTRONG WESTERMAN HATTORI MCLELAND AND NAUGHTON 1725 K STRRET NW	EETS TOTAL INDER FILING FEE ATTORNEY'S POCKET NO.
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